

Notice of References Cited	Application/Control No. 09/740,889	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Tan Dean D. Nguyen	Art Unit 3629	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,112,312	08-2000	Parker et al.	714/32
	C	US-6,353,904	03-2002	Le, Dai Minh	714/726
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NON-PATENT DOCUMENTS

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